

## STF9NK60ZD, STP9NK60ZD

## N-channel 600 V - 0.85 Ω - 7 A - TO-220FP, TO-220 SuperFREDMesh™ Power MOSFET

Datasheet - obsolete product

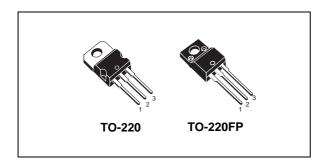
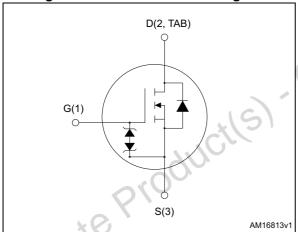


Figure 1. Internal schematic diagram



#### **Features**

Туре	V <sub>DS</sub>	R <sub>DS(on)</sub> max.	I <sub>D</sub>	P <sub>TOT</sub>
STF9NK60ZD	600 V	< 0.95 Ω	7 A	30 W
STP9NK60ZD	600 V	< 0.95 Ω	7 A	125 W

- · Very high dv/dt capability
- 100% avalanche tested
- Gate charge minimized
- · Low intrinsic capacitances
- Fast internal recovery diode

#### **Application**

Switching applications

#### **Description**

The SuperFREDMesh™ series associates all advantages of reduced on-resistance, Zener gate protection and very high dv/dt capability with a fast body-drain recovery diode. Such series complements the "FDmesh™" advanced technology.

Table 1. Device summary

Order code	Marking	Package	Packaging
STF9NK60ZD	F9NK60ZD	TO-220FP	Tube
STP9NK60ZD	P9NK60ZD	TO-220	Tube

## **Contents**

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# 1 Electrical ratings

Table 2. Absolute maximum ratings

		Valu		
Symbol	Parameter	TO-220	TO-220FP	Unit
V <sub>DS</sub>	Drain-source voltage	600	)	V
V <sub>GS</sub>	Gate-source voltage	± 3	0	V
I <sub>D</sub>	Drain current (continuous) at T <sub>C</sub> = 25 °C	7	7 <sup>(1)</sup>	Α
I <sub>D</sub>	Drain current (continuous) at T <sub>C</sub> = 100 °C	4.3	4.3 <sup>(1)</sup>	Α
I <sub>DM</sub> <sup>(2)</sup>	Drain current (pulsed)	28	28 <sup>(1)</sup>	Α
P <sub>TOT</sub>	Total dissipation at T <sub>C</sub> = 25 °C	125	30	W
	Derating factor	1	0.24	W/°C
V <sub>ESD(G-S)</sub>	Gate-source ESD (HBM-C=100 pF, R=1.5 kΩ)	400	0	V
dv/dt (3)	Peak diode recovery voltage slope	15	j	V/ns
V <sub>ISO</sub>	Insulation withstand voltage (RMS) from all three leads to external heat sink (t = 1 s; T <sub>C</sub> = 25 °C)	3	2500	V
T <sub>j</sub> T <sub>stg</sub>	Operating junction temperature Storage temperature	-55 to	150	°C

- 1. Limited only by maximum temperature allowed.
- 2. Pulse width limited by safe operating area.
- 3.  $I_{SD} \leq$  7 A, di/dt  $\leq$  500 A/ $\mu$ s,  $V_{DD}$  = 80% $V_{(BR)DSS}$ .

Table 3. Thermal data

Symbol	Parameter	Valu	Unit	
Symbol	Farameter	TO-220	TO-220FP	Onit
R <sub>thj-pcb</sub>	Thermal resistance junction-pcb max. (when mounted on minimum footprint)	30		°C/W
R <sub>thj-case</sub>	Thermal resistance junction-case max.	1	4.16	°C/W
R <sub>thj-amb</sub>	Thermal resistance junction-ambient max.	62.5		°C/W
T <sub>I</sub>	Maximum lead temperature for soldering purpose	300		°C

**Table 4. Avalanche characteristics** 

Symbol Parameter		Max. value	Unit
I <sub>AR</sub>	Avalanche current, repetitive or not-repetitive (pulse width limited by $T_j$ max.)	7	Α
E <sub>AS</sub>	Single pulse avalanche energy (starting $T_j = 25$ °C, $I_D = I_{AR}$ , $V_{DD} = 50$ V)	235	mJ

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## 2 Electrical characteristics

(T<sub>case</sub> = 25 °C unless otherwise specified)

Table 5. On /off states

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V <sub>(BR)DSS</sub>	Drain-source breakdown voltage	$I_D = 1 \text{ mA}, V_{GS} = 0$	600			V
I <sub>DSS</sub>	Zero gate voltage drain current (V <sub>GS</sub> = 0)	$V_{DS}$ = max. rating $V_{DS}$ = max. rating, $T_{C}$ = 125 °C			1 50	μA μA
I <sub>GSS</sub>	Gate-body leakage current (V <sub>DS</sub> = 0)	V <sub>GS</sub> = ± 20 V			±10	μΑ
V <sub>GS(th)</sub>	Gate threshold voltage	$V_{DS} = V_{GS}, I_{D} = 100 \mu A$	2.5	3.5	4.5	٧
R <sub>DS(on)</sub>	Static drain-source on- resistance	$V_{GS} = 10 \text{ V}, I_D = 3.5 \text{ A}$	70	0.85	0.95	Ω

Table 6. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
g <sub>fs</sub> <sup>(1)</sup>	Forward transconductance	V <sub>DS</sub> = 15 V <sub>,</sub> I <sub>D</sub> = 3.5 A	-	5.3		S
C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub>	Input capacitance Output capacitance Reverse transfer capacitance	$V_{DS} = 25 \text{ V, f} = 1 \text{ MHz, V}_{GS} = 0$	-	1110 135 30		pF pF pF
C <sub>oss eq</sub> <sup>(2)</sup>	Equivalent output capacitance	V <sub>GS</sub> = 0, V <sub>DS</sub> = 0 to 480 V	-	72		pF
$egin{array}{c} Q_{g} \ Q_{gs} \ Q_{gd} \end{array}$	Total gate charge Gate-source charge Gate-drain charge	$V_{DD} = 480 \text{ V}, I_D = 7 \text{ A},$ $V_{GS} = 10 \text{ V}$ (see Figure 17)	-	41 8.7 21	53	nC nC nC

<sup>1.</sup> Pulsed: pulse duration =  $300 \mu s$ , duty cycle 1.5%.

<sup>2.</sup>  $C_{oss\ eq}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$ .

Table 7. Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t <sub>d(on)</sub> t <sub>r</sub> t <sub>d(off)</sub> t <sub>f</sub>	Turn-on delay time Rise time Turn-off-delay time Fall time	$V_{DD} = 300 \text{ V}, I_{D} = 3.5 \text{ A}$ $R_{G} = 4.7 \Omega, V_{GS} = 10 \text{ V}$ Figure 16	-	11.4 13.6 23.1 15	-	ns ns ns
t <sub>r(Voff)</sub> t <sub>f</sub> t <sub>C</sub>	Off-voltage rise time Fall time Cross-overtime	$V_{DD} = 480 \text{ V}, I_{D} = 7 \text{ A},$ $R_{G} = 4.7 \Omega, V_{GS} = 10 \text{ V}$ Figure 16	-	11 8 20	-	ns ns ns

Table 8. Source-drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I <sub>SD</sub>	Source-drain current		0		7	Α
I <sub>SDM</sub> <sup>(1)</sup>	Source-drain current (pulsed)				28	Α
V <sub>SD</sub> <sup>(2)</sup>	Forward on voltage	I <sub>SD</sub> = 7 A, V <sub>GS</sub> = 0	-		1.6	V
t <sub>rr</sub>	Reverse recovery time	$I_{SD} = 7 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}$		130		ns
$Q_{rr}$	Reverse recovery charge	$V_{DD} = 30 \text{ V}$	-	550		nC
I <sub>RRM</sub>	Reverse recovery current	Figure 21		8.4		Α
t <sub>rr</sub>	Reverse recovery time	$I_{SD} = 7 \text{ A, di/dt} = 100 \text{ A/}\mu\text{s}$		176		ns
$Q_{rr}$	Reverse recovery charge	$V_{DD} = 30 \text{ V}, T_j = 150 ^{\circ}\text{C}$	-	880		nC
$I_{RRM}$	Reverse recovery current	Figure 21		10		Α

- 1. Pulse width limited by safe operating area.
- 2. Pulsed: pulse duration =  $300 \mu s$ , duty cycle 1.5%.

Table 9. Gate-source Zener diode

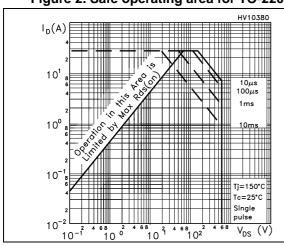
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
BV <sub>GSO</sub> <sup>(1)</sup>	Gate-source breakdown voltage	Igs=± 1 mA (open drain)	30			V

The built-in back-to-back Zener diodes have specifically been designed to enhance not only the device's ESD capability, but also to make them safely absorb possible voltage transients that may occasionally be applied from gate to source. In this respect the Zener voltage is appropriate to achieve an efficient and cost-effective intervention to protect the device's integrity. These integrated Zener diodes thus avoid the usage of external components.

## 2.1 Electrical characteristics (curves)

Figure 2. Safe operating area for TO-220

Figure 3. Thermal impedance for TO-220



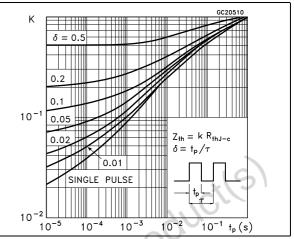
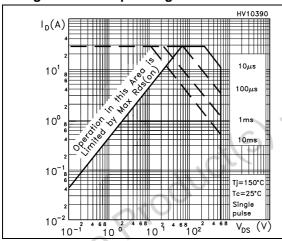


Figure 4. Safe operating area for TO-220FP

Figure 5. Thermal impedance for TO-220FP



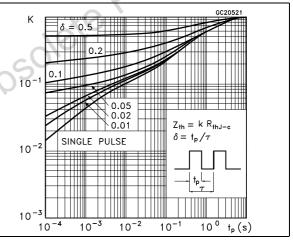
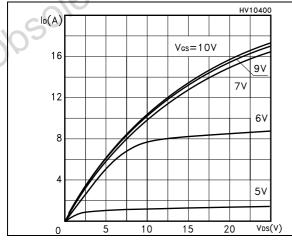
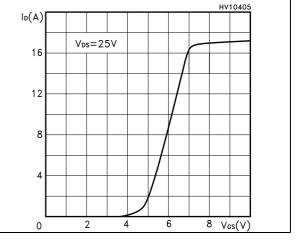


Figure 6. Output characteristics

Figure 7. Transfer characteristics





47/

1.05

0.95

0.9

-50

Figure 8. Normalized B<sub>VDSS</sub> vs temperature

Figure 9. Static drain-source on-resistance

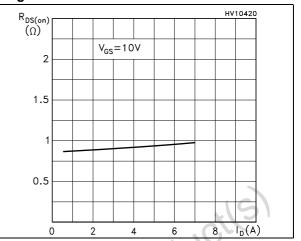


Figure 10. Gate charge vs gate-source voltage

0

50

100

150 T∫℃

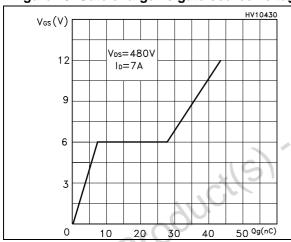


Figure 11. Capacitance variations

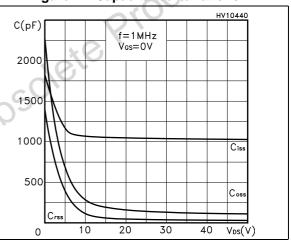


Figure 12. Normalized gate threshold voltage vs temperature

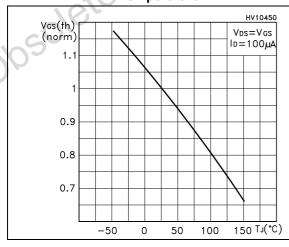
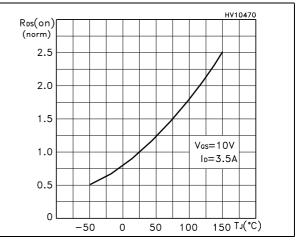


Figure 13. Normalized on-resistance vs temperature



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Figure 14. Source-drain diode forward characteristics

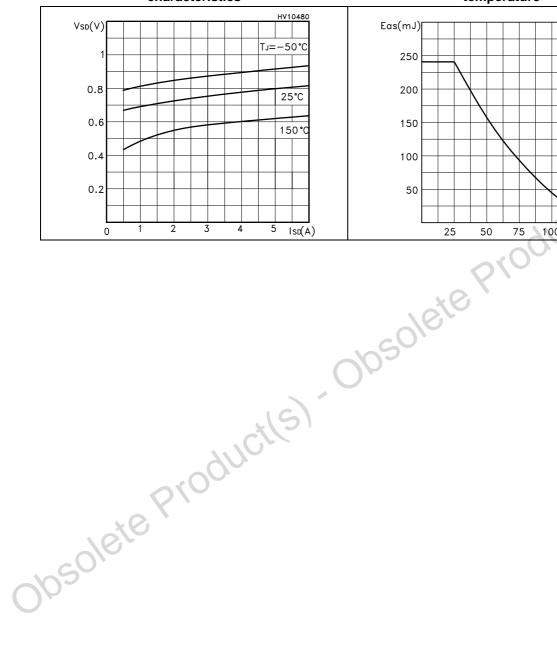
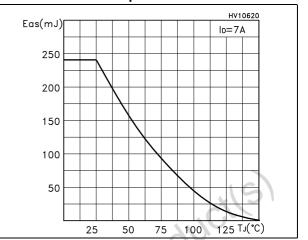


Figure 15. Maximum avalanche energy vs temperature



#### 3 Test circuits

Figure 16. Switching time test circuit for resistive load

Figure 17. Gate charge test circuit

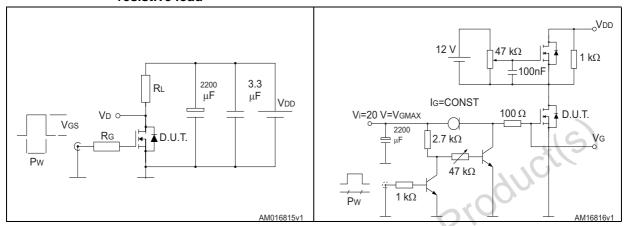


Figure 18. Test circuit for inductive load switching and diode recovery times

Figure 19. Unclamped inductive load test circuit

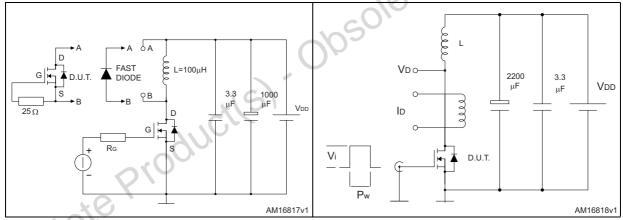
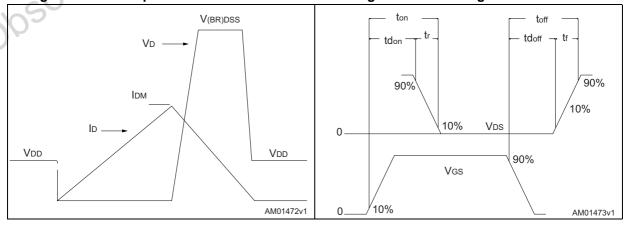


Figure 20. Unclamped inductive waveform

Figure 21. Switching time waveform



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# 4 Package mechanical data

n order to meet environmental requirements, ST offers these devices in different grades of ECOPACK<sup>®</sup> packages, depending on their level of environmental compliance. ECOPACK<sup>®</sup> specifications, grade definitions and product status are available at: <a href="https://www.st.com">www.st.com</a>. ECOPACK<sup>®</sup> is an ST trademark.

Table 10. TO-220 type A mechanical data

	Dim		mm	
	Dim.	Min.	Тур.	Max.
	А	4.40		4.60
	b	0.61		0.88
	b1	1.14		1.70
	С	0.48		0.70
	D	15.25		15.75
	D1		1.27	
	E	10		10.40
	е	2.40	WS	2.70
	e1	4.95		5.15
	F	1.23		1.32
	H1	6.20		6.60
	J1	2.40		2.72
	L	13		14
	L1	3.50		3.93
	L20		16.40	
\ 0	L30		28.90	
-0/6	ØP	3.75		3.85
psole	Q	2.65		2.95

øΡ Ε D <u>D1</u> L20 L30 305018 P(b1(X3) <u>L</u>1 - *b (Х3)* 0015988\_typeA\_Rev\_T

Figure 22. TO-220 drawing

Table 11. TO-220FP mechanical data

	Dim	mm		
	Dim.	Min.	Тур.	Max.
	Α	4.4		4.6
	В	2.5		2.7
	D	2.5		2.75
	E	0.45		0.7
	F	0.75		1
	F1	1.15		1.70
	F2	1.15		1.70
	G	4.95		5.2
	G1	2.4		2.7
	Н	10	0	10.4
	L2		16	
	L3	28.6	16/	30.6
	L4	9.8	60,	10.6
	L5	2.9	100	3.6
	L6	15.9		16.4
	L7	9		9.3
	Dia	3		3.2
Jbsole	tePro	due		

Ф Dia *L2 L7* L3 F1 L4 F2 Ε -G1-7012510\_Rev\_K\_B

Figure 23. TO-220FP drawing

## 5 Revision history

**Table 12. Document revision history** 

Date	Revision	Changes
19-Jul-2013	1	First release. The part numbers STF9NK60ZD and STP9NK60ZD were previously included in datasheet with DocID9573.



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